10/614,354 SONDERMAN ET AL. **Notice of References Cited** Examiner Art Unit

Application/Control No.

Page 1 of 1 Khiem D. Nguyen 2823

Applicant(s)/Patent Under

Reexamination

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,133,746	10-2000	Fang et al.	324/769
	В	US-			
	С	US-			
	D	US-			
	Ε	US-			
	F	US-			
	G	US-			
	Н	US-			
	ı	US-			
	J	US-			
	К	US-			71-0-1
	L	US-			
	М	US-			·

FOREIGN PATENT DOCUMENTS

	()	TONEIGH FAILH DOCUMENTO							
*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification			
	N								
	0								
	Р	W. Control of the con							
	Q								
-	R		0.00						
	S								
	Т								

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	v	
	w	
	x	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.